

## PCN# 20150325000 Topside symbol change for CC3100/3200 Devices to correct the ECAT classification to G4 Information Only

Date: 3/31/2015 To: Newark/Farnell PCN

Dear Customer:

This is an information-only announcement of a change to a device that is currently offered by Texas Instruments.

The changes discussed within this PCN are for your information only.

Any negotiated alternative change requirements will be provided via the customer's defined process. Customers with previously negotiated, special requirements will be handled separately. Any inquiries should be directed to your local Field Sales Representative.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (<u>PCN ww admin team@list.ti.com</u>).

Sincerely,

PCN Team SC Business Services

## 20150325000 Attachment: 1

# **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

#### DEVICE

### **CUSTOMER PART NUMBER**

CC3100R11MRGC CC3200R1M1RGC CC3200R1M2RGC

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Technical details of this Product Change follow on the next page(s).

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	LLLL = Lot Trace Code							
	S = Primary Site Code X = Secondary Site Code							
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Assembly Site	t Shipp	ing Label (not actua	al product label)	
Amkor P3	Asse	mbly Site Origin (22L)	ASO: AP3	ECAT:G3
Amkor P3	Asse	mbly Site Origin (22L)	ASO: AP3	ECAT:G4
TEXAS	(			actual product label)
TEXAS INSTRUMENTS MADE IN: Malaysi 2DC: 22: MSL 2 /260C/1 YEL MSL 1 /235C/UNLIN OPT: ITEM: LBL: 5A (L) Product Affected	AR SEAL 0 M 03/29/ T0:175		(1P) SN74LS07NSR (Q) 2000 (D) 033 (31T) LOT: 3959047ML (4W) TKY (1T) 7523483 (P) (2P) REV: (V) 0033: (20L) CSO: SHE (21L) CCO: (22L) ASO: MLA (23L) ACO:	6 ISI2
2DC: 2d: MSL '2 /260C/1 YE/ MSL 1 /235C/UNLIN OPT: ITEM: LBL: 5A (L)	a AR SEAL 0 03/29/ TO:175		(1P) SN74LS07NSR (Q) 2000 (D) 033 (31T) LOT: 3959047ML (4W) TKY (1T) 7523483 (P) (2P) REV: (V) 00333 (20L) CSO: SHE (21L) CCO:	6 ISI2

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com